A Complete Bibliography of Publications in *Technometrics* for the decade 1990–1999

Nelson H. F. Beebe
University of Utah
Department of Mathematics, 110 LCB
155 S 1400 E RM 233
Salt Lake City, UT 84112-0090
USA

Tel: +1 801 581 5254
FAX: +1 801 581 4148

E-mail: `beebe@math.utah.edu`, `beebe@acm.org`,
`beebe@computer.org` (Internet)
WWW URL: `https://www.math.utah.edu/~beebe/`

03 June 2024
Version 1.03

Title word cross-reference

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